

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3418	(716/1,4).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/06/05 14:51
L2	1561	(700/121).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/06/05 14:51
L3	3436	(707/203-205).CCLS.	US-PGPUB; USPAT	OR	OFF	2006/06/05 14:51
L4	8329	1 2 3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:12
L5	2023	application near3 tier	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:05
L6	34	4 and 5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 14:52
L7	2116	application near3 tier data near3 access near3 tier	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:05
L8	99	application near3 tier and data near3 access near3 tier	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:05
L9	0	application near3 tier and data near3 access near3 tier and fabricat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:06
L10	14	application near3 tier and data near3 access near3 tier and (integrated near3 circuit or ic or semiconductor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/05 15:06
L11	0	(extensible data analysis integrated circuit fabrication application tier node select\$4 dynamic\$4 user reader format).clm.	USPAT	AND	ON	2006/06/05 15:12